August 2000

# FQPF70N10

#### 100V N-Channel MOSFET

### **General Description**

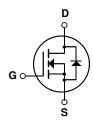
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as audio amplifier, high efficiency switching DC/DC converters, and DC motor control.

#### **Features**

- 35A, 100V,  $R_{DS(on)}$  = 0.023 $\Omega$  @V<sub>GS</sub> = 10 V Low gate charge ( typical 85 nC)
- Low Crss (typical 150 pF)
- Fast switching
- · 100% avalanche tested
- · Improved dv/dt capability
- 175°C maximum junction temperature rating





# **Absolute Maximum Ratings** T<sub>C</sub> = 25 °C unless otherwise noted

Symbol	Parameter		FQPF70N10	Units	
$V_{DSS}$	Drain-Source Voltage		100	V	
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°	°C)	35	Α	
	- Continuous (T <sub>C</sub> = 100	)℃)	24.7	Α	
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	140	Α	
V <sub>GSS</sub>	Gate-Source Voltage		± 25	V	
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	1300	mJ	
I <sub>AR</sub>	Avalanche Current	(Note 1)	35	Α	
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	6.2	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	6.0	V/ns	
$P_{D}$	Power Dissipation (T <sub>C</sub> = 25 °C)		62	W	
	- Derate above 25 ℃		0.41	W/°C	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +175	∞	
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	€	

# **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		2.42	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	Test Conditions	s	Min	Тур	Max	Units
Off Cha	racteristics						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		100			V
$\Delta BV_{DSS}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced	d to 25℃		0.1		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0 V				1	μΑ
		V <sub>DS</sub> = 80 V, T <sub>C</sub> = 150 °C				10	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	$V_{GS} = 25 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	$V_{GS} = -25 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
On Cha	racteristics						
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 μA		2.0		4.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 17.5 A			0.019	0.023	Ω
9FS	Forward Transconductance	V <sub>DS</sub> = 40 V, I <sub>D</sub> = 17.5 A	(Note 4)		38		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0  MHz			720 150	940 200	pF pF pF
	ng Characteristics						
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 50 \text{ V}, I_{D} = 70 \text{ A},$ $R_{G} = 25 \Omega$			30	70	ns
t <sub>r</sub>	Turn-On Rise Time				470	950	ns
t <sub>d(off)</sub>	Turn-Off Delay Time				130	270	ns
t <sub>f</sub>	Turn-Off Fall Time	1	(Note 4, 5)		160	330	ns
Qg	Total Gate Charge	V <sub>DS</sub> = 80 V, I <sub>D</sub> = 70 A,			85	110	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V			16	-	nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note 4, 5)			42	1	пC
Drain-S	Source Diode Characteristics at Maximum Continuous Drain-Source Dio	ode Forward Current	S			35	A
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode F					140	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 35 \text{ A}$				1.5	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_S = 70 \text{ A,}$ $dI_F / dt = 100 \text{ A/}\mu\text{s}$ (Note 4)			110		ns
Q <sub>rr</sub>	Reverse Recovery Charge				430		nC

- Notes: 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 1.59mH,  $I_{AS} = 35A$ ,  $V_{DD} = 25V$ ,  $R_G = 25 \Omega$ , Starting  $T_J = 25 ^{\circ}C$  3.  $I_{SD} \le 70A$ ,  $di'dt \le 300A'\mu s$ ,  $V_{DD} \le BV_{DSS}$ , Starting  $T_J = 25 ^{\circ}C$  4. Pulse Test : Pulse width  $\le 300\mu s$ , Duty cycle  $\le 2\%$  5. Essentially independent of operating temperature

# **Typical Characteristics**

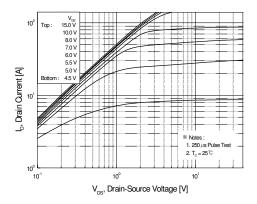


Figure 1. On-Region Characteristics

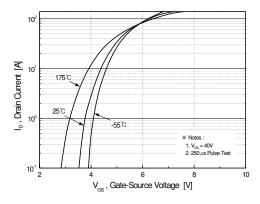


Figure 2. Transfer Characteristics

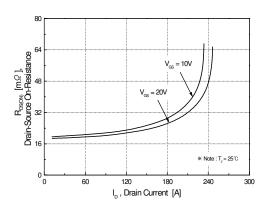


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

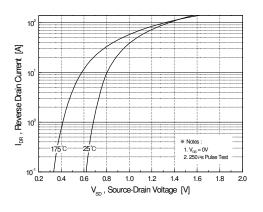


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

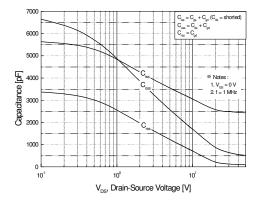


Figure 5. Capacitance Characteristics

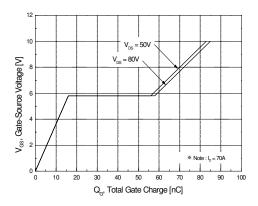
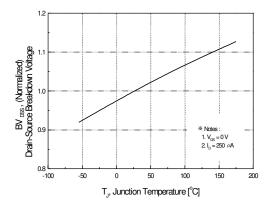


Figure 6. Gate Charge Characteristics





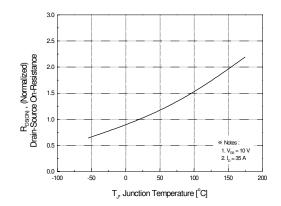
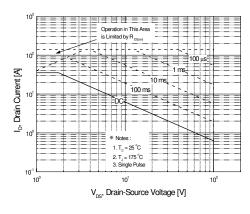


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



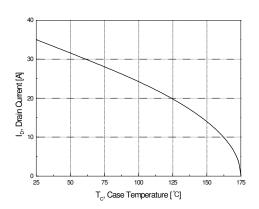


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

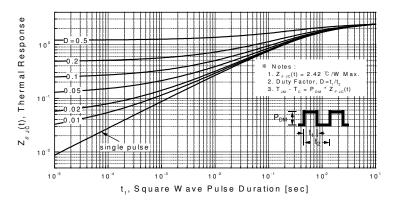
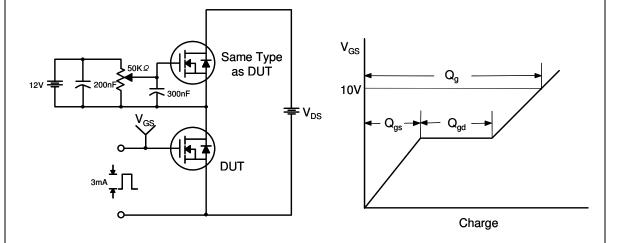


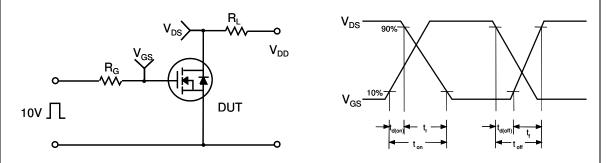
Figure 11. Transient Thermal Response Curve

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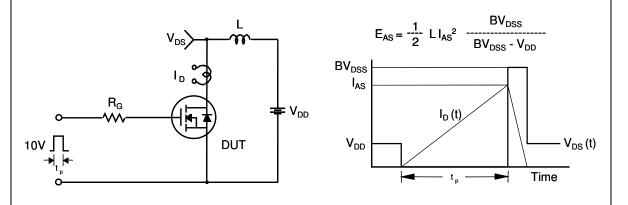
# **Gate Charge Test Circuit & Waveform**



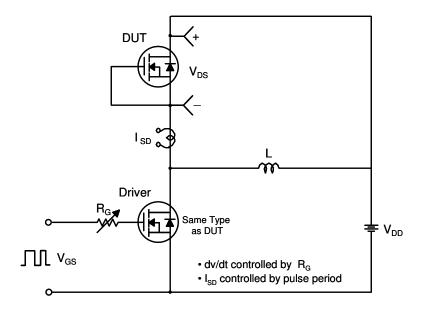
## **Resistive Switching Test Circuit & Waveforms**

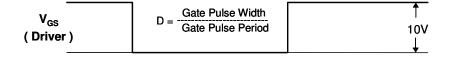


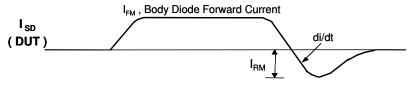
# **Unclamped Inductive Switching Test Circuit & Waveforms**



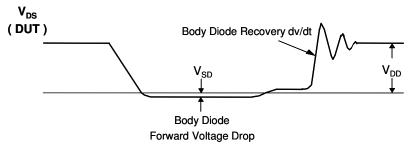
## Peak Diode Recovery dv/dt Test Circuit & Waveforms

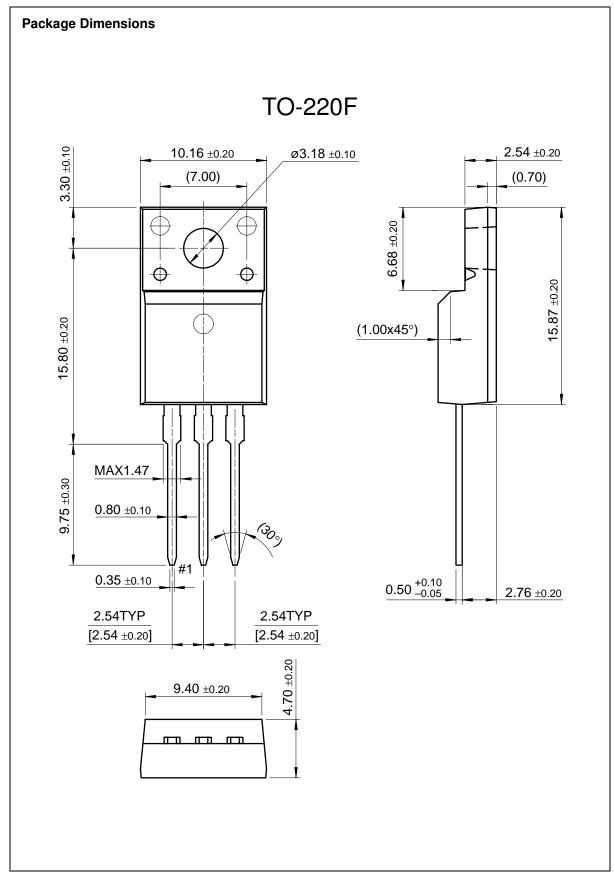






Body Diode Reverse Current





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